



## Advanced Studies in Coordinate Measuring Technique

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Deadline for manuscript  
submissions:

**closed (20 November 2025)**

### Message from the Guest Editor

This Special Issue focus on the advanced studies of coordinate measuring techniques. We mainly include the extended version of the conference paper from the XV International Scientific Conference ‘Coordinate Measuring Technique’ CMT24. However, we also welcome submissions from other research groups.

We welcome original research, case studies, and practical implementations focused on, but not limited to, the following:

- development in a field of coordinate measuring techniques,
- coordinate measuring machines,
- theory of coordinate measurements,
- measurement uncertainty,
- traceability and inspection of coordinate measuring systems,
- use of metrology in the production of machine elements,
- the role and tasks of metrology in quality assurance systems,
- new trends in surface measurements,
- visualization and virtualization techniques,
- metrology in The Fourth Industrial Revolution,
- coordinate metrology education,
- geometrical product specification.





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## Editor-in-Chief

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## Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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